**Product data sheet** 

## 1. General description

WG40N120UAW1 uses advanced Fine Trench Field-stop IGBT technology with anti-parallel diode in TO-247 package. This device is part of the Ultra-Fast series of IGBTs, which represents an optimum compromise between conduction and switching losses to maximize the efficiency of high switching frequency converter.



### 2. Features and benefits

- · Maximum junction temperature 175 °C
- Ultra-Fast switching series
- · Positive Temperature efficient for Easy Parallel Operating
- · Very soft, fast recovery anti-parallel diode
- · EMI Improved Design

### 3. Applications

- Solar inverter
- PFC
- · Welding converters
- UPS
- · Mid to high switching frequency applications

### 4. Quick reference data

#### Table 1. Quick reference data

Symbol	Parameter		Notes	Value			Unit
V <sub>CE</sub>	Collector-emitter voltage, T <sub>j</sub> ≥ 25 °C			1200			V
I <sub>C</sub>	DC collector current, limited by $T_{j(max)}$ $T_C = 100  ^{\circ}C$				40		Α
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static characteristics							
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}; I_{C} = 40 \text{ A}; T_{j} = 25 \text{ °C}$		-	1.75	2.25	V

# 5. Pinning information

#### Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		•C
2	С	collector		
3	E	emitter		(\
mb	С	mounting base; connected to collector	TO247	G E sym200

# 6. Ordering information

### **Table 3. Ordering information**

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WG40N120UAW1	TO247	WG40N120UAW1Q	Tube	30	TO247P	09-Mar-2023

## 7. Marking

#### **Table 4. Marking codes**

Type number	Marking codes
WG40N120UAW1	G40N120 UAW1

# 8. Limiting values

### Table 5. Limiting values

Symbol	Parameter	Notes	Value	Unit
V <sub>CE</sub>	Collector-emitter voltage, T <sub>j</sub> ≥ 25 °C		1200	V
I <sub>C</sub>	DC collector current, limited by $T_{j(max)}$ $T_{c}$ = 25 °C $T_{c}$ = 100 °C		80 40	А
I <sub>C(puls)</sub>	Pulsed collector current, t <sub>p</sub> limited by T <sub>j(max)</sub>		120	А
-	Turn off safe operating area $V_{CE} \le 1200 \text{ V}, T_j \le 175 ^{\circ}\text{C}, t_p = 1 \mu\text{s}$		120	А
I <sub>F</sub>	Diode forward current, limited by $T_{j(max)}$ $T_{c}$ = 25 °C $T_{c}$ = 100 °C		40 20	А
I <sub>Fpuls</sub>	Diode pulsed current, t <sub>p</sub> limited by T <sub>j(max)</sub>		60	Α
$V_{GE}$	Gate-emitter voltage		±20	V
P <sub>tot</sub>	Power dissipation $T_c$ = 25 °C Power dissipation $T_c$ = 100 °C		750 375	W
T <sub>stg</sub>	Storage temperature		-55 to +150	°C
$T_{jmax}$	Maximum operating junction temperature		175	°C
-	Peak soldering temperture		260	°C
M	Mounting Torque with washer		0.55	Nm

### 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R <sub>th(j-c)</sub>	IGBT thermal resistance from junction to case			-	0.20	-	K/W
R <sub>th(j-c)</sub>	Diode thermal resistance from junction to case			-	1.35	-	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient			-	40	-	K/W

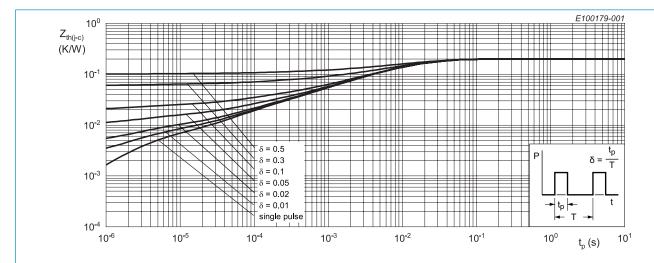


Fig. 1. Transient thermal impedance from junction to case as a function of pulse duration; IGBT

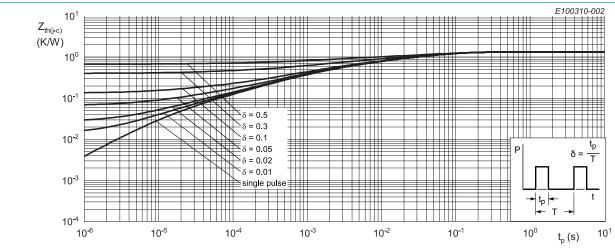


Fig. 2. Transient thermal impedance from junction to case as a function of pulse duration; Diode

## 10. Characteristics

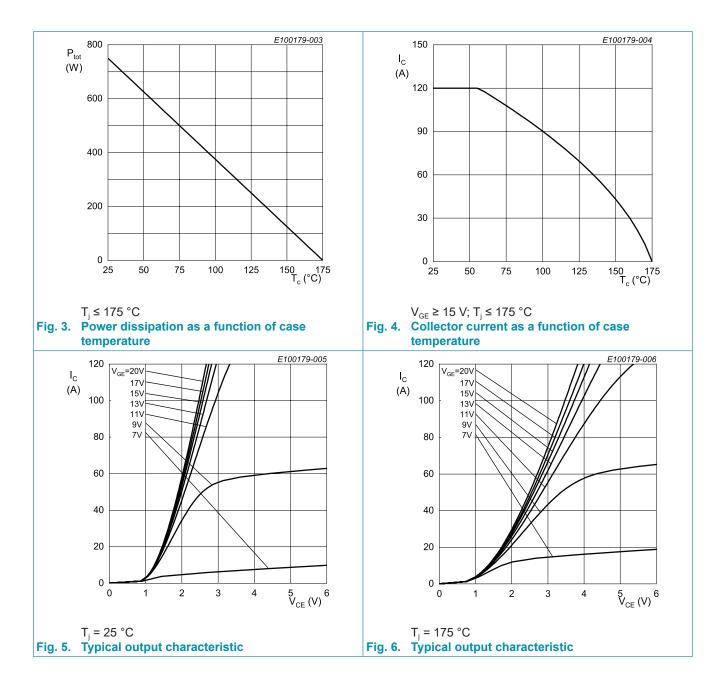
### **Table 7. Characteristics**

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
V <sub>CE(sat)</sub> Collector-emitter saturation voltage	Collector-emitter saturation	$V_{GE} = 15 \text{ V}; I_C = 40 \text{ A}; T_j = 25 ^{\circ}\text{C}$		-	1.75	2.25	V
	$V_{GE}$ = 15 V; $I_{C}$ = 40 A; $T_{j}$ = 175 °C		-	2.35	-	V	
V <sub>F</sub>	Diode forward voltage	$V_{GE} = 0 \text{ V}; I_F = 20 \text{ A}; T_j = 25 \text{ °C}$		-	1.95	-	V
	V <sub>GE</sub> = 0 V; I <sub>F</sub> = 20 A; T <sub>j</sub> = 175 °C		-	1.87	-	V	
$V_{\text{GE(th)}}$	Gate-emitter threhold voltage	$I_{\rm C}$ = 0.5 mA; $V_{\rm CE}$ = $V_{\rm GE}$		4.2	5.3	6.4	V
I <sub>CES</sub> Zero gate voltage collector current	-	V <sub>CE</sub> = 1200 V; V <sub>GE</sub> = 0 V; T <sub>j</sub> = 25 °C		-	-	250	μA
	$V_{CE} = 1200 \text{ V}; V_{GE} = 0 \text{ V};$ $T_j = 175 \text{ °C}$		-	-	10	mA	
g <sub>fs</sub>	Transconductance	$V_{CE} = 20 \text{ V}; I_{C} = 40 \text{ A}$		-	30	-	S
Dynamic	characteristics						
C <sub>ies</sub>	Input capacitance	$V_{CE} = 30 \text{ V}; V_{GE} = 0 \text{ V}; f = 1 \text{ MHz};$		-	6330	-	pF
C <sub>oes</sub>	Output capacitance	T <sub>j</sub> = 25 °C		-	129	-	pF
C <sub>res</sub>	Reverse transfer capacitance			-	29	-	pF
$Q_{G}$	Gate charge	$V_{CC} = 960 \text{ V}; I_{C} = 40 \text{ A}; V_{GE} = 15 \text{ V};$ $T_{i} = 25 \text{ °C}$		-	210	-	nC

# 11. Switching Characteristics

Table 8. Switching Characteristics, Inductive Load

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
IGBT cha	racteristics						
$t_{d(on)}$	Turn-on delay time	T <sub>j</sub> = 25 °C;		-	41	-	nS
t <sub>r</sub>	Rise time	$V_{CC} = 600 \text{ V}; I_C = 40 \text{ A};$ $V_{GE} = 15 \text{V} / 0 \text{V};$		-	28	-	nS
$t_{\text{d(off)}}$	Turn-off delay time	$R_{\rm G}=3.6~\Omega$		-	149	-	nS
t <sub>f</sub>	Fall time			-	48	-	nS
E <sub>on</sub>	Turn-on energy			-	1.85	-	mJ
E <sub>off</sub>	Turn-off energy			-	1.1	-	mJ
E <sub>ts</sub>	Total switching energy			-	2.95	-	mJ
t <sub>d(on)</sub>	Turn-on delay time	T <sub>j</sub> = 175 °C;		-	37	-	nS
t <sub>r</sub>	Rise time	$V_{CC} = 600 \text{ V}; I_{C} = 40 \text{ A};$ $V_{GE} = 15 \text{V} / 0 \text{V};$		-	28	-	nS
$t_{d(off)}$	Turn-off delay time	$R_G = 3.6 \Omega$		-	184	-	nS
t <sub>f</sub>	Fall time			-	103	-	nS
E <sub>on</sub>	Turn-on energy			-	2.65	-	mJ
E <sub>off</sub>	Turn-off energy			-	1.9	-	mJ
E <sub>ts</sub>	Total switching energy			-	4.55	-	mJ
Diode cha	aracteristics			1		1	
t <sub>rr</sub>	Reverse recovery time	T <sub>j</sub> = 25 °C;		-	68	-	nS
Q <sub>r</sub>	Reverse recovery charge	$V_R = 600 \text{ V}; I_F = 20 \text{ A};$ $dI_F/dt = 800 \text{A/us}$		-	1003	-	nC
I <sub>RM</sub>	Reverse recovery peak current			-	25	-	А
t <sub>rr</sub>	Reverse recovery time	T <sub>j</sub> = 175 °C;		-	178	-	nS
Q <sub>r</sub>	Reverse recovery charge	$V_R = 600 \text{ V}; I_F = 20 \text{ A};$ $dI_F/dt = 800 \text{A/us}$		-	2564	-	nC
I <sub>RM</sub>	Reverse recovery peak current	F		-	30	-	А



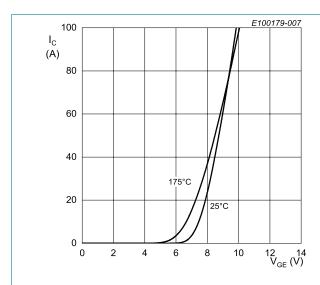
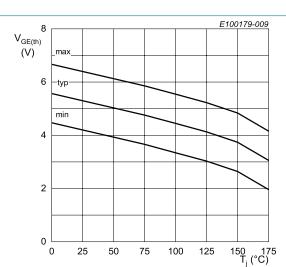
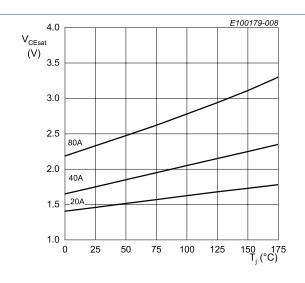


Fig. 7. Typical transfer characteristic

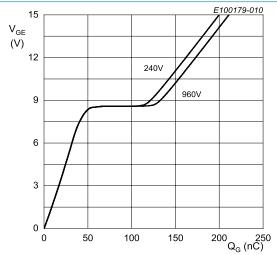
 $V_{CE} = 20 \text{ V}$ 



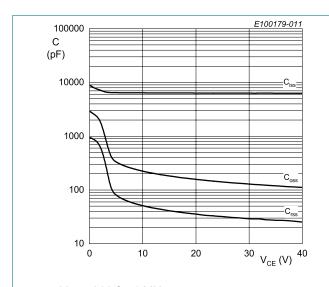
 $I_c$  = 500  $\mu A$  Fig. 9. Gate-emitter threshold voltage as a function of junction temperature



V<sub>GE</sub> = 15 V
Fig. 8. Typical collector-emitter saturation voltage as a function of junction temperature



 $I_{\rm C}$  = 40 A Fig. 10. Typical gate charge



V<sub>GE</sub> = 0 V; f = 1 MHz
Fig. 11. Typical capacitance as a function of collector-emitter voltage

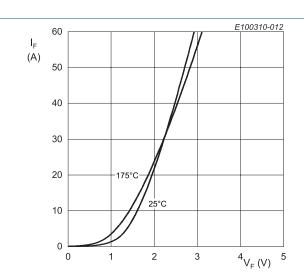
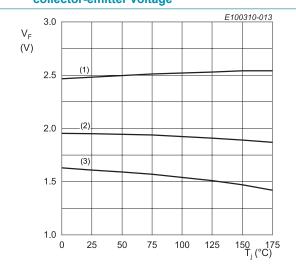
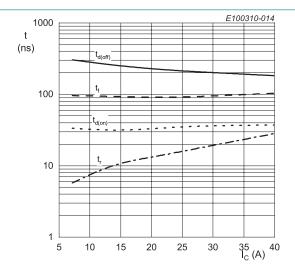


Fig. 12. Typical diode forward current as a function of forward voltage



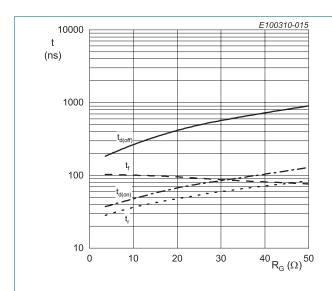
(1)  $I_F = 40 \text{ A}$ (2)  $I_F = 20 \text{ A}$ (3)  $I_F = 10 \text{ A}$ 

Fig. 13. Typical diode forward voltage as a function of junction temperature



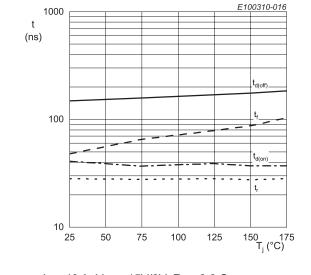
 $\rm R_g$  = 3.6  $\Omega;$   $\rm V_{GE}$  = 15V/0V; T\_j = 175 °C;  $\rm V_{CE}$  = 600 V; inductive load

Fig. 14. Typical switching times as a function of collector current



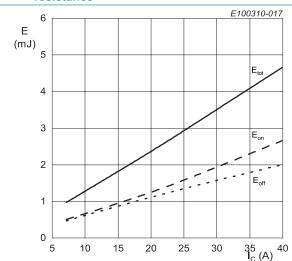
 $I_C$  = 40 A;  $V_{GE}$  = 15V/0V;  $T_j$  = 175 °C;  $V_{CE}$  = 600 V; inductive load

Fig. 15. Typical switching times as a function of gate resistance



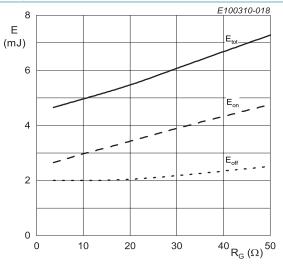
 $I_{C}$  = 40 A;  $V_{GE}$  = 15V/0V;  $R_{g}$  = 3.6  $\Omega$ ;  $V_{CE}$  = 600 V; inductive load

Fig. 16. Typical switching times as a function of junction temperature



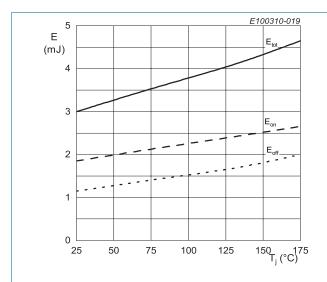
 $R_g = 3.6~\Omega;~V_{GE} = 15V/0V;~T_j = 175~^{\circ}C;\\ V_{CE} = 600~V;~inductive~load$  Fig. 17. Typical switching energy losses as a function

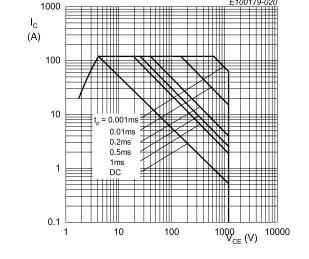
of collector current



 $I_{\text{C}}$  = 40 A;  $V_{\text{GE}}$  = 15V/0V;  $T_{j}$  = 175 °C;  $V_{\text{CE}}$  = 600 V; inductive load

Fig. 18. Typical switching energy losses as a function of gate resistance





 $I_{C}$  = 40 A;  $V_{GE}$  = 15V/0V;  $R_{g}$  = 3.6 Ω;  $V_{CE}$  = 600 V; inductive load

Fig. 20. Forward bias safe operating area

Fig. 19. Typical switching energy losses as a function of junction temperature

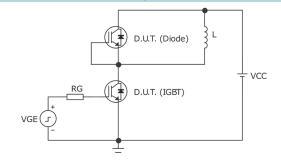


Fig. 21. Test circuit for inductive load switching

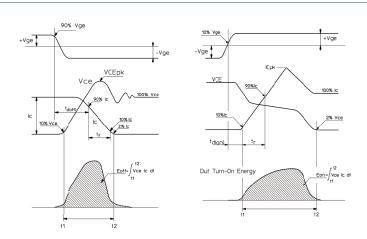
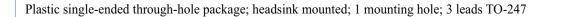
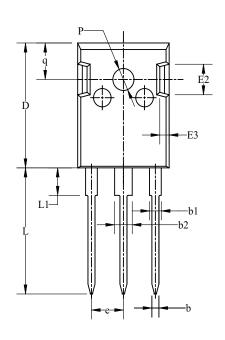


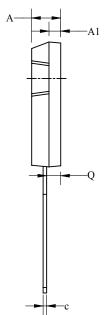
Fig. 22. Definition of switching times and losses

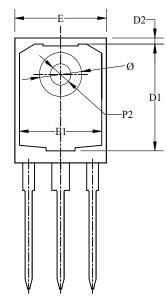
# 12. Package outline



TO247







Dim	All Dim	ensions in M	illimeters
Dilli	Min	Тур	Max
A	4.70	4.95	5.20
A1	1.90	2.00	2.10
b	1.00	1.20	1.40
b1	1.80	2.00	2.20
b2	2.80	3.00	3.20
с	0.50	0.60	0.70
D	20.30	20.45	20.60
D1	17.28	17.48	17.68
D2	0.80	1.00	1.20
Е	15.45	15.60	15.75
E1	13.82	14.02	14.22
E2	4.80	5.00	5.20
E3	1.40	1.60	1.80
e		5.45 BSC	
L	20.40	20.65	20.90
L1	4.25	4.50	4.75
P2	3.40	3.50	3.60
P	3.50	3.60	3.70
Q	2.20	2.40	2.60
q	5.78	5.98	6.18
Ø	7.10	7.19	7.30

### 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 07 January 2025

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